



SIXTH SEMESTER B.TECH. (INSTRUMENTATION AND CONTROL ENGG.)

END SEMESTER DEGREE EXAMINATION, JUNE - 2019

SUBJECT: DIGITAL SYSTEM DESIGN [ICE 4001]

TIME: 3 HOURS

MAX. MARKS: 50

Instructions to candidates : Answer ALL questions and missing data may be suitably assumed.

- 1A What is the size of the smallest ROM that is needed to implement the following?
- (a) A 4-to-1 MUX
 - (b) An 8-to-3 priority encoder
- 1B Find a minimum-row PLA table to implement the following functions:
 $x(A,B,C,D) = \sum m(3, 6, 7, 11, 15)$
 $y(A,B,C,D) = \sum m(1, 3, 4, 7, 9, 13)$
 $z(A,B,C,D) = \sum m(4, 6, 8, 10, 11, 12, 14, 15)$
- 1C Write a VHDL code to develop a half adder using data flow model. Using this as a component, build four-bit full adder. Draw logic/block diagram wherever required. (2+3+5)
- 2A Evaluate: $A \& \text{NOT } B \text{ AND } C \text{ SRA } 3 \text{ XOR } D$. Determine the resulting value.
where $A = "110"$; $B = "000"$; $C = "111000"$; $D = "110110"$.
- 2B Write a VHDL code for the combinational circuit as shown in Fig. Q 2B using conditional assignment statement.

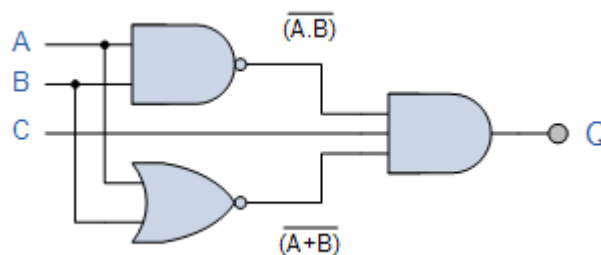


Fig. Q2B

- 2C Briefly outline the purpose of the following VHDL modelling constructs.
- i) Signal attributes
 - ii) function declaration
 - iii) component declaration and instantiation
 - iv) package declaration
 - v) Generics

(2+3+5)

- 3A Draw a state graph and state table to implement a sequence detector for detecting a sequence “1101” (overlapping method) using mealy machine.
- 3B What are the different wait statements available in VHDL? Mention their use with examples.
- 3C With a state graph, write and explain the VHDL code for traffic light controller realization in PAL22V10. (2+3+5)
- 4A Explain SRAM and Anti-fuse programming technology used to make the FPGAs field programmable.
- 4B Explain the concept of test bench for the verification of design through simulation.
- 4C How to attach a package to the VHDL module? Explain with an example. (4+3+3)
- 5A Explain the architecture of Xilinx Spartan FPGA with a suitable diagrams.
- 5B Find a minimum set of tests that will test all single stuck-at-0 and stuck-at-1 faults in the network shown in Fig. Q5B.

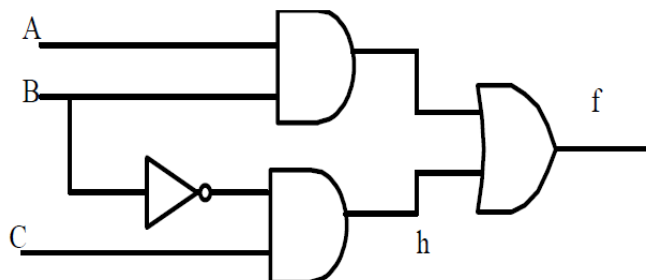


Fig. Q5B

- 5C Explain testing of sequential logic using scan path testing. (4+3+3)
